

## Maximum Ratings @T<sub>A</sub> = 25°C unless otherwise specified

Characteristic			Symbol	Value	Unit
Drain-Source Voltage			V <sub>DSS</sub>	-20	V
Gate-Source Voltage			V <sub>GSS</sub>	±8	V
Continuous Drain Current	Steady State	T <sub>A</sub> = 25°C (Note 4)	I <sub>D</sub>	-1.14	A
		T <sub>A</sub> = 85°C (Note 4)		-0.83	
		T <sub>A</sub> = 25°C (Note 5)		-0.82	
Pulsed Drain Current (Note 6)			I <sub>DM</sub>	-4.0	A

## Thermal Characteristics @T<sub>A</sub> = 25°C unless otherwise specified

Characteristic		Symbol	Value	Unit
Power Dissipation	(Note 4)	P <sub>D</sub>	930	mW
	(Note 5)		490	mW
Thermal Resistance, Junction to Ambient	(Note 4)	R <sub>θJA</sub>	135	°C/W
	(Note 5)		256	°C/W
Operating and Storage Temperature Range		T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C

- Notes:
4. For a device surface mounted on 15mm x 15mm x 1.6mm FR4 PCB with high coverage of 2oz copper, in still air conditions; the device is measured when operating in a steady-state condition.
  5. Same as note 4, except the device is mounted on minimum recommended pad layout.
  6. Device mounted on minimum recommended pad layout test board, 10μs pulse duty cycle = 1%.

## Thermal Characteristics

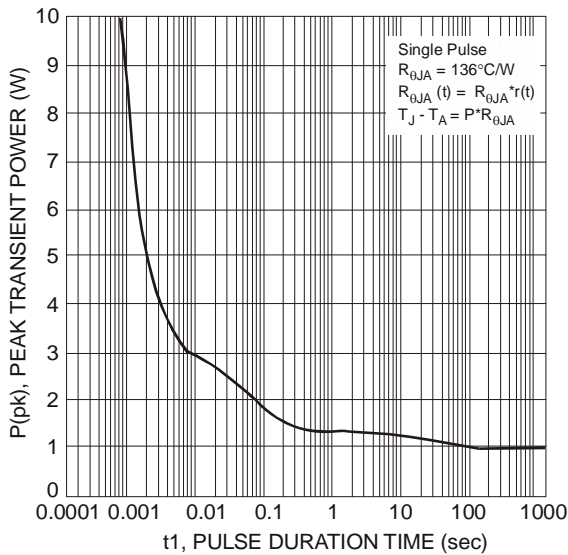


Fig. 1 Single Pulse Maximum Power Dissipation

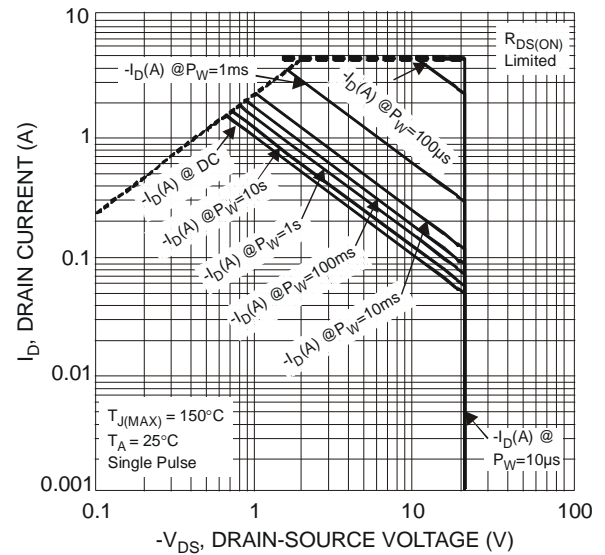


Fig. 2 SOA, Safe Operation Area

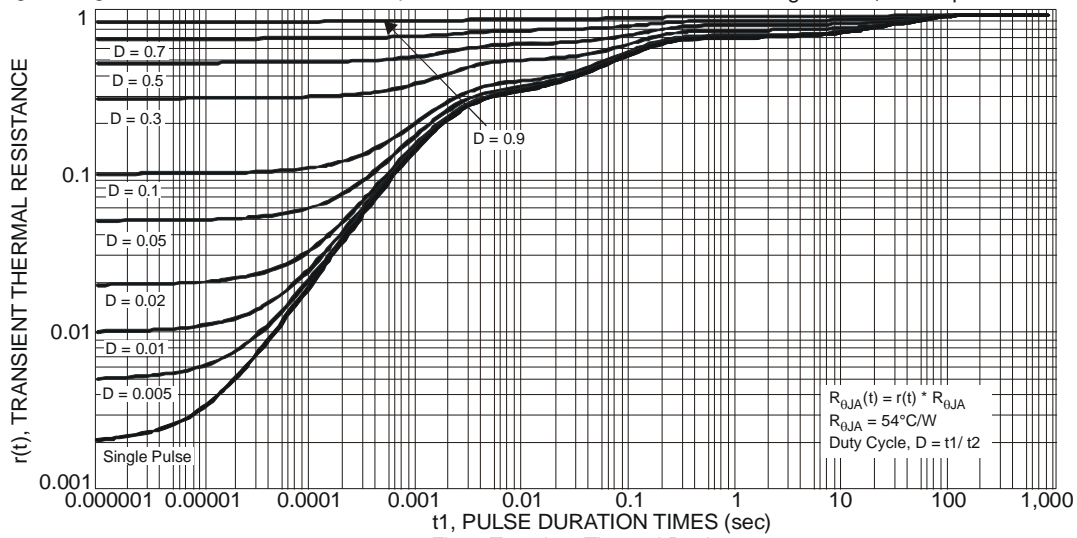


Fig. 3 Transient Thermal Resistance

**Electrical Characteristics** @T<sub>A</sub> = 25°C unless otherwise specified

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
<b>OFF CHARACTERISTICS (Note 7)</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-20	-	-	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = -250μA
Zero Gate Voltage Drain Current T <sub>J</sub> = 25°C	I <sub>DSS</sub>	-	-	-1	μA	V <sub>DS</sub> = -20V, V <sub>GS</sub> = 0V
Gate-Source Leakage	I <sub>GSS</sub>	-	-	±10	μA	V <sub>GS</sub> = ±8V, V <sub>DS</sub> = 0V
<b>ON CHARACTERISTICS (Note 7)</b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	-0.45	-0.7	-1.2	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA
Static Drain-Source On-Resistance	R <sub>DS(on)</sub>	-	-	495	mΩ	V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -800mA
				730		V <sub>GS</sub> = -2.5V, I <sub>D</sub> = -700mA
				960		V <sub>GS</sub> = -1.8V, I <sub>D</sub> = -100mA
				1300		V <sub>GS</sub> = -1.5V, I <sub>D</sub> = -100mA
Forward Transfer Admittance	Y <sub>fs</sub>	50	-	-	mS	V <sub>DS</sub> = -3V, I <sub>D</sub> = -300mA
Diode Forward Voltage	V <sub>SD</sub>	-	-	-1.2	V	V <sub>GS</sub> = 0V, I <sub>S</sub> = -300mA
<b>DYNAMIC CHARACTERISTICS</b>						
Input Capacitance	C <sub>iss</sub>	-	76.5	-	pF	V <sub>DS</sub> = -10V, V <sub>GS</sub> = 0V, f = 1.0MHz
Output Capacitance	C <sub>oss</sub>	-	13.7	-	pF	
Reverse Transfer Capacitance	C <sub>rss</sub>	-	10.7	-	pF	
Gate Resistance	R <sub>g</sub>	-	195	-	Ω	V <sub>DS</sub> = 0V, V <sub>GS</sub> = 0V, f = 1MHz
Total Gate Charge (Note 8)	Q <sub>g</sub>	-	1.5	-	nC	V <sub>GS</sub> = -8V, V <sub>DS</sub> = -15V, I <sub>D</sub> = -1A
Total Gate Charge (Note 8)	Q <sub>g</sub>	-	1.0	-	nC	V <sub>GS</sub> = -4.5V, V <sub>DS</sub> = -15V, I <sub>D</sub> = -1A
Gate-Source Charge	Q <sub>gs</sub>	-	0.2	-	nC	
Gate-Drain Charge	Q <sub>gd</sub>	-	0.3	-	nC	
Turn-On Delay Time	t <sub>D(on)</sub>	-	7.1	-	ns	V <sub>DS</sub> = -10V, -I <sub>D</sub> = 1A V <sub>GS</sub> = -4.5V, R <sub>G</sub> = 6Ω
Turn-On Rise Time	t <sub>r</sub>	-	8.0	-	ns	
Turn-Off Delay Time	t <sub>D(off)</sub>	-	31.7	-	ns	
Turn-Off Fall Time	t <sub>f</sub>	-	18.5	-	ns	

Notes: 7. Short duration pulse test used to minimize self-heating effect.  
 8. Guarantee by design.

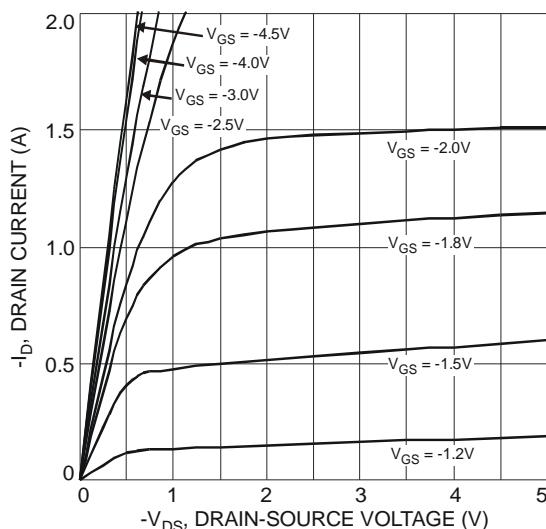


Fig. 4 Typical Output Characteristic

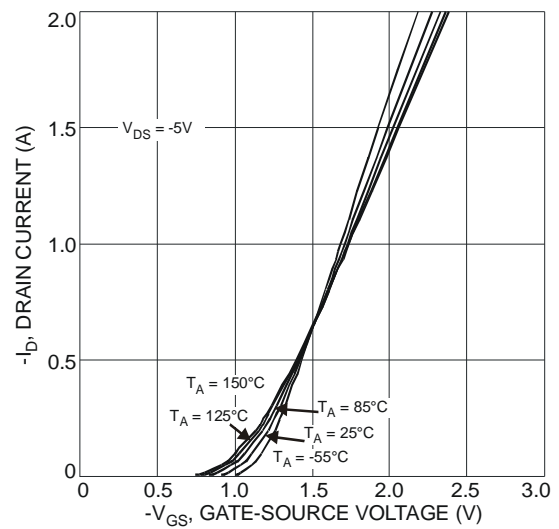


Fig. 5 Typical Transfer Characteristic

**DMP21D0UFD**

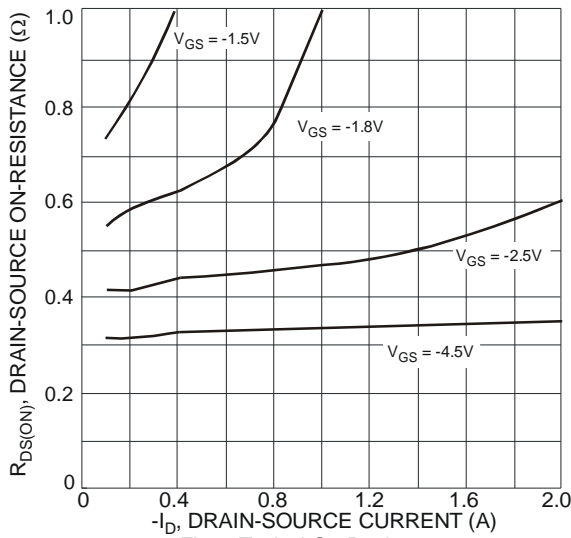


Fig. 6 Typical On-Resistance  
vs. Drain Current and Gate Voltage

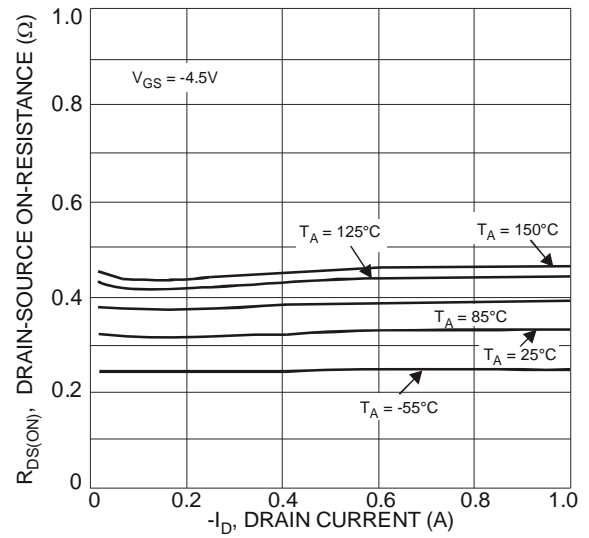


Fig. 7 Typical On-Resistance  
vs. Drain Current and Temperature

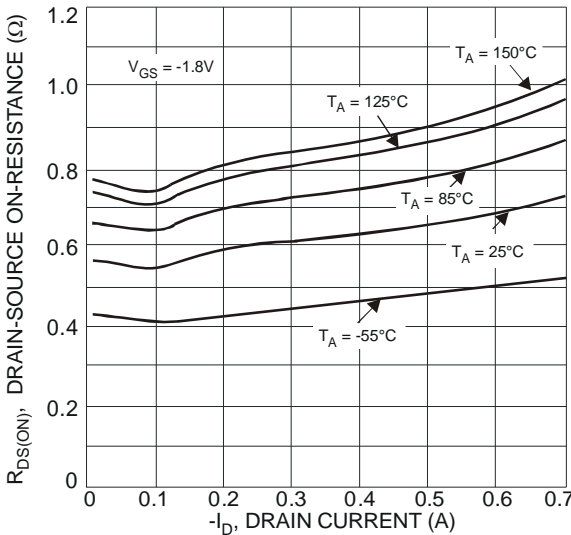


Fig. 8 Typical On-Resistance  
vs. Drain Current and Temperature

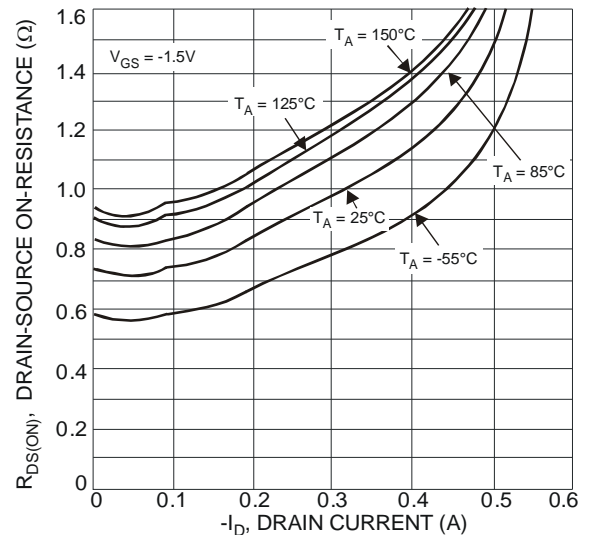


Fig. 9 Typical On-Resistance  
vs. Drain Current and Temperature

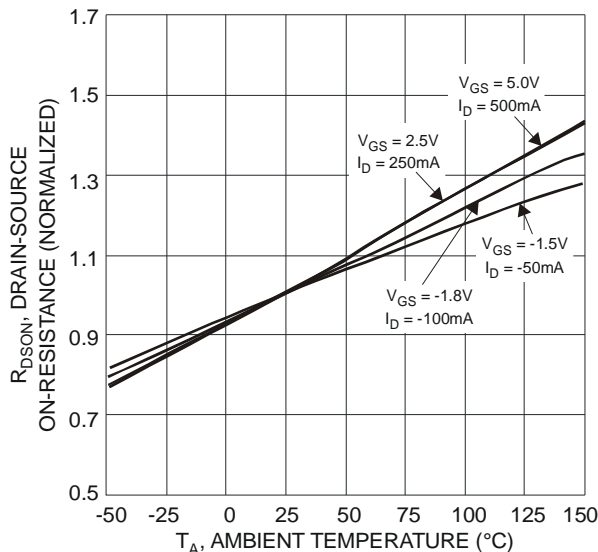


Fig. 10 On-Resistance Variation with Temperature

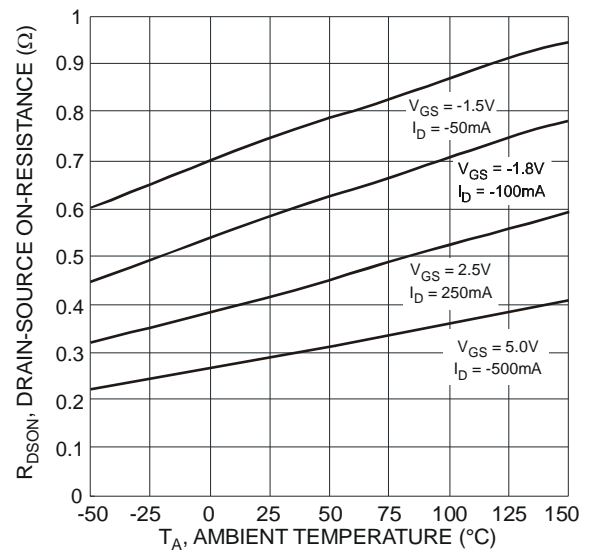


Fig. 11 On-Resistance Variation with Temperature

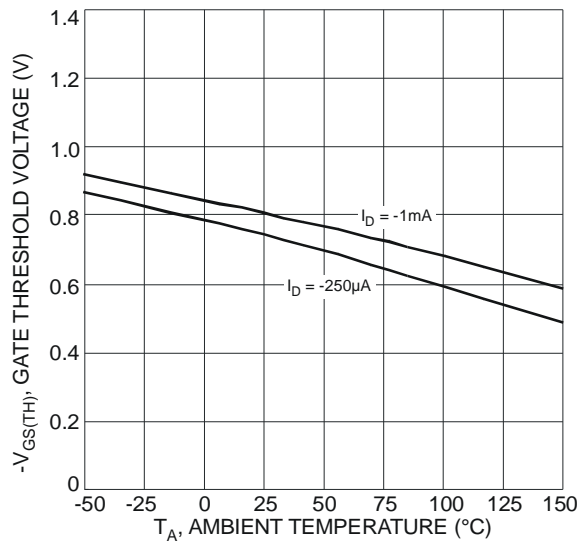


Fig. 12 Gate Threshold Variation vs. Ambient Temperature

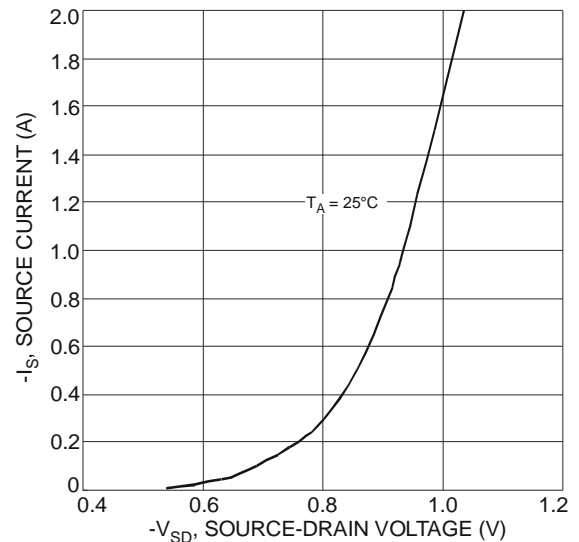


Fig. 13 Diode Forward Voltage vs. Current

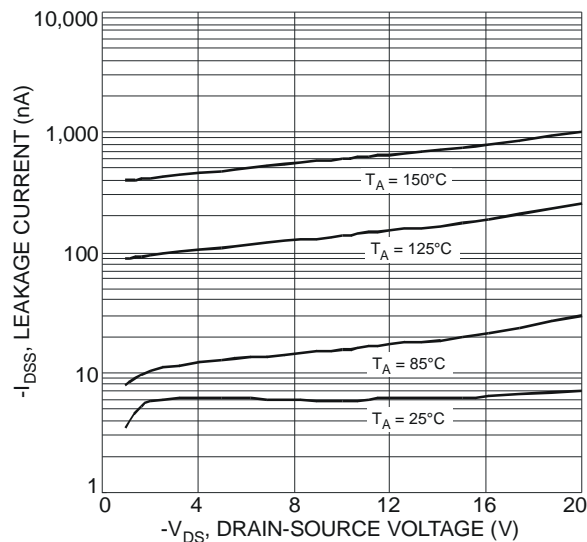


Fig. 14 Typical Leakage Current vs. Drain-Source Voltage

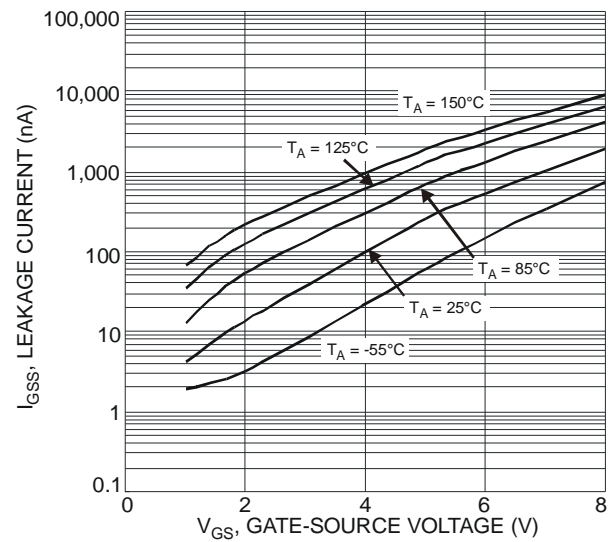


Fig. 15 Leakage Current vs. Gate-Source Voltage

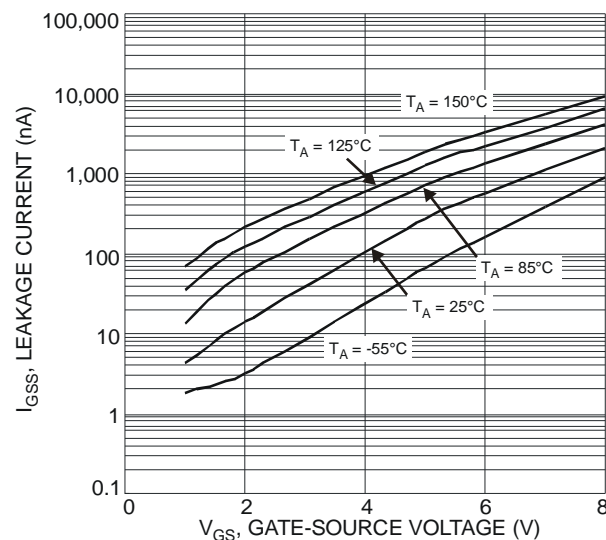


Fig. 16 Leakage Current vs. Gate-Source Voltage

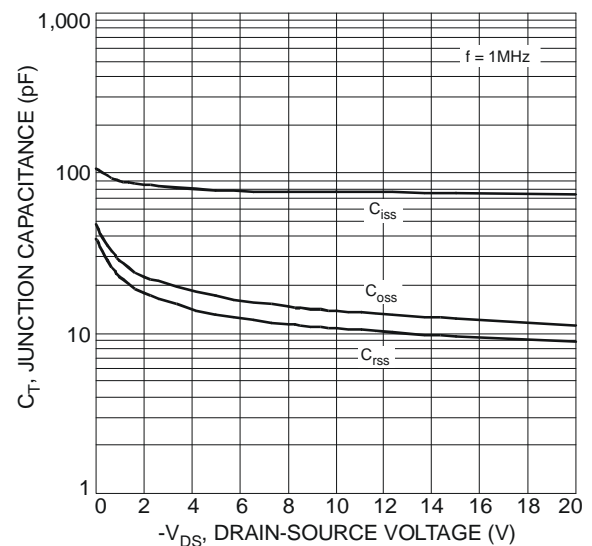


Fig. 17 Typical Junction Capacitance

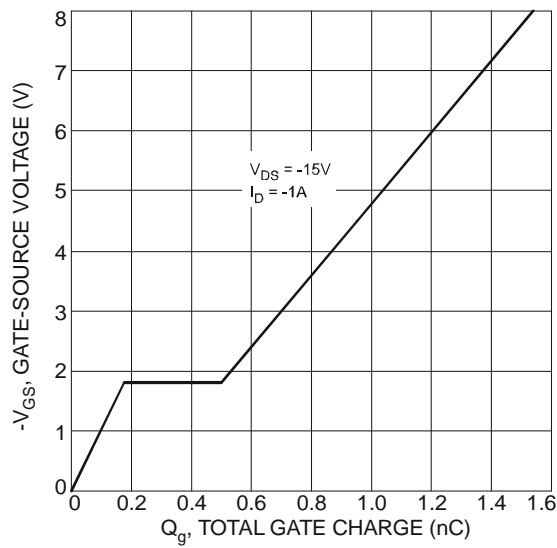
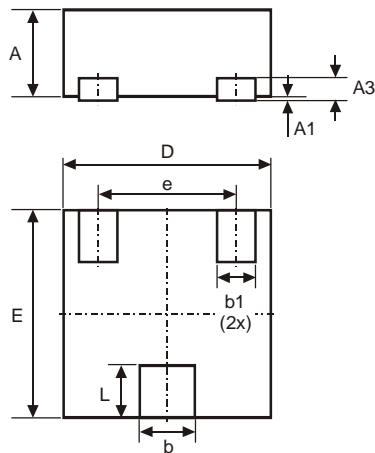


Fig. 18 Gate-Charge Characteristics

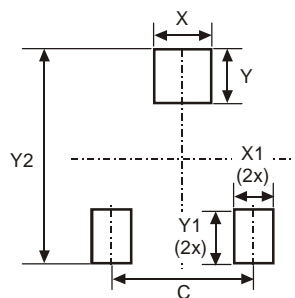
## Package Outline Dimensions



X1-DFN1212-3			
Dim	Min	Max	Typ
A	0.47	0.53	0.50
A1	0	0.05	0.02
A3	-	-	0.13
b	0.27	0.37	0.32
b1	0.17	0.27	0.22
D	1.15	1.25	1.20
E	1.15	1.25	1.20
e	-	-	0.80
L	0.25	0.35	0.30

All Dimensions in mm

## Suggested Pad Layout



Dimensions	Value (in mm)
C	0.80
X	0.42
X1	0.32
Y	0.50
Y1	0.50
Y2	1.50

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